

Never Stand Still

Faculty of Engineering

School of Chemical Engineering

Project Background

❖ Cuprous Oxide (Cu₂O):

- Earth abundant & non-toxic
- Ease in forming numerous **well-defined morphologies**
- p-type semiconductor with **favourable band potentials** for redox reactions

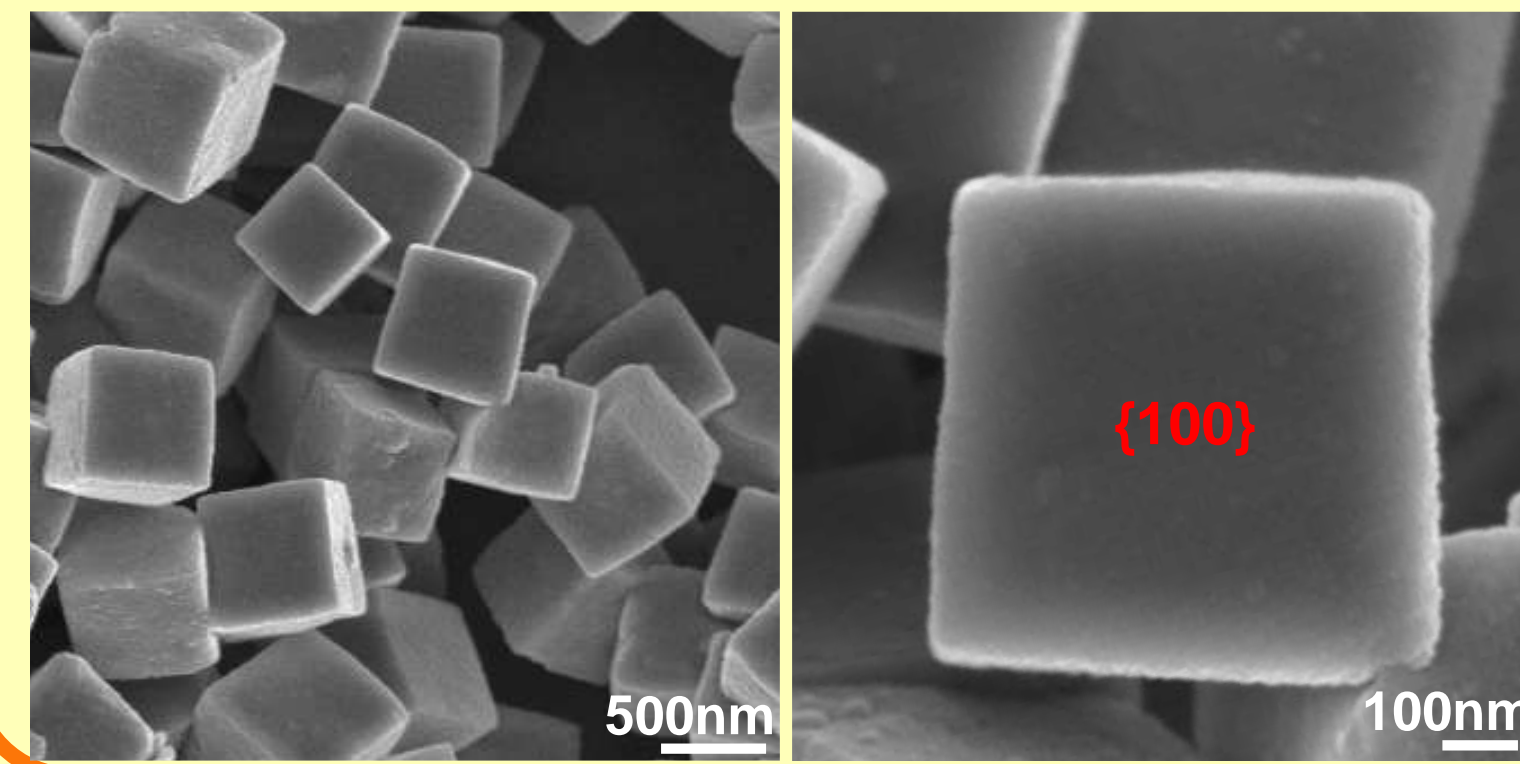
❖ Facet-engineering of Cu₂O:

- Facet-dependent properties
 - ✓ Surface adsorption ability
 - ✓ Surface electronic band structure
 - ✓ **Surface defect density**
- Influence the intrinsic carrier dynamics

Morphology and Structure

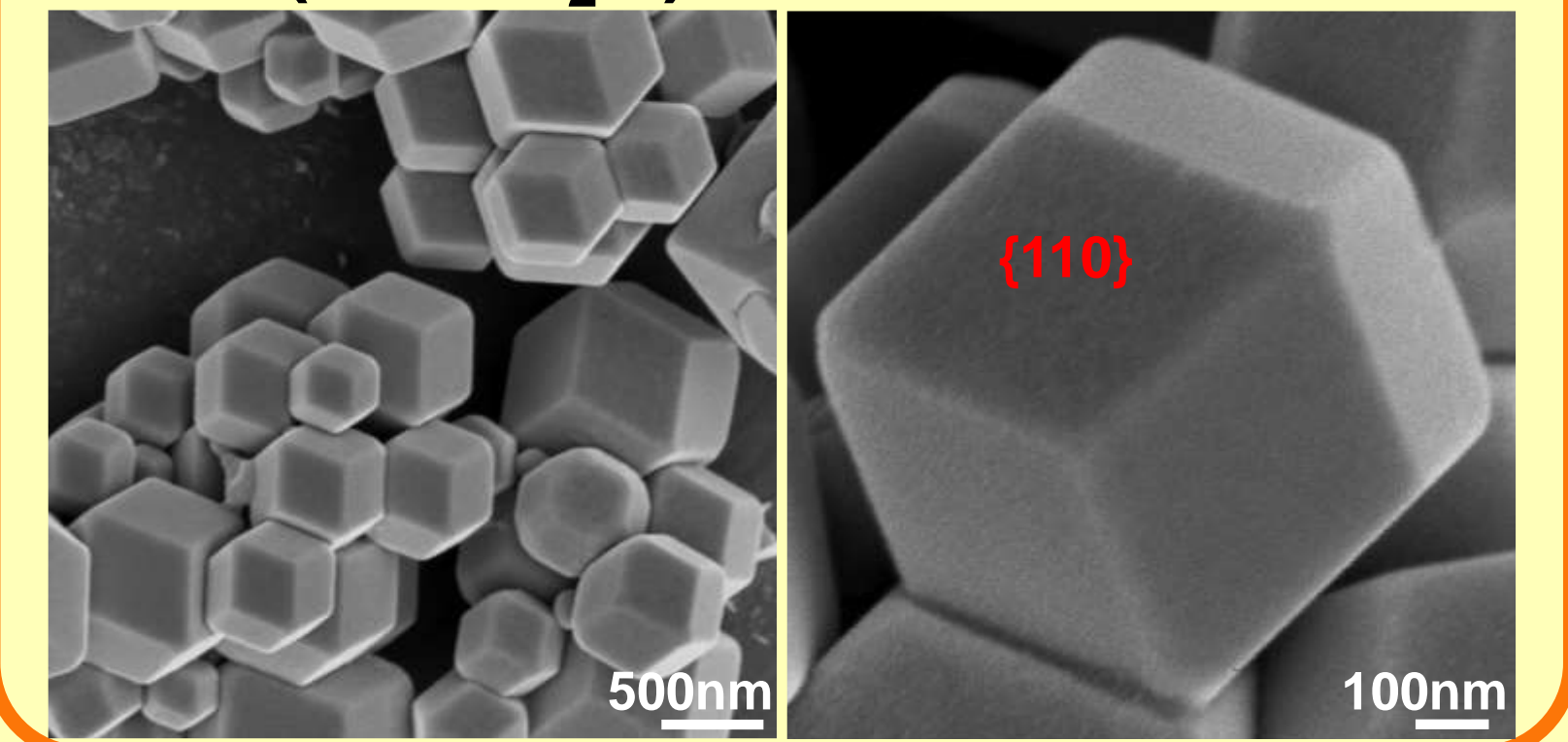
60 °C,
no oleic acid

Cubic
(CB-Cu₂O)



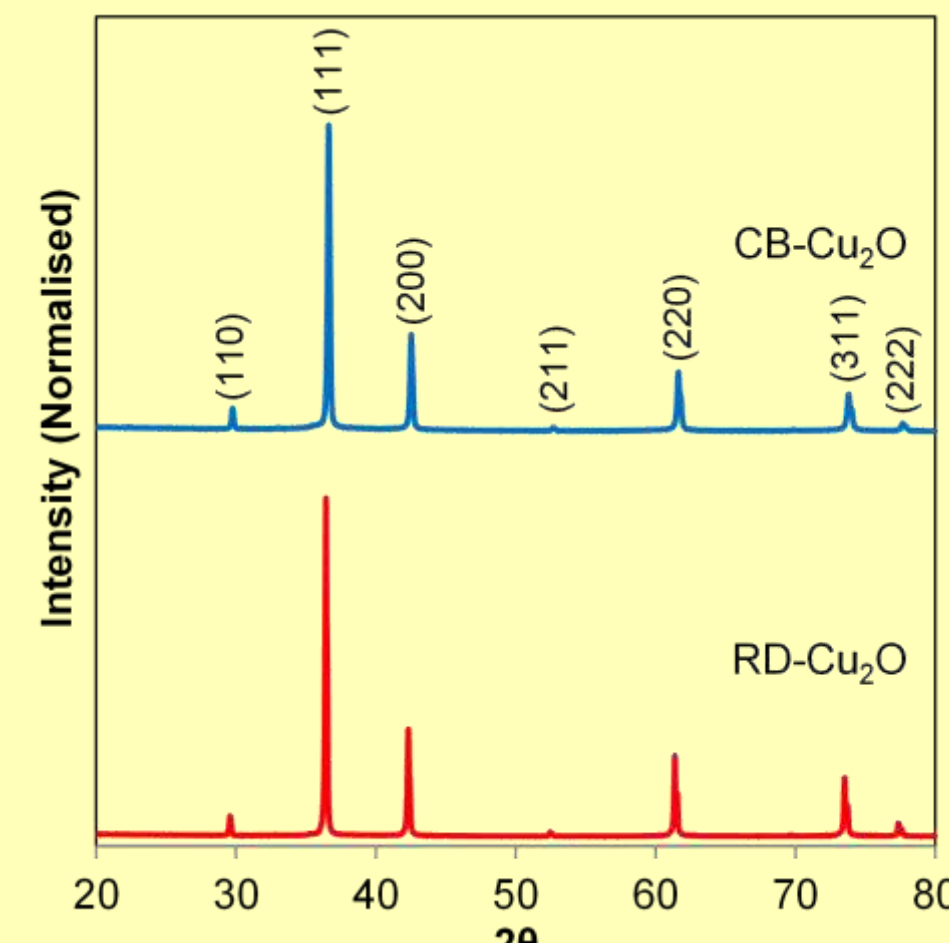
100 °C,
12 mL oleic acid

Rhombic Dodecahedral
(RD-Cu₂O)



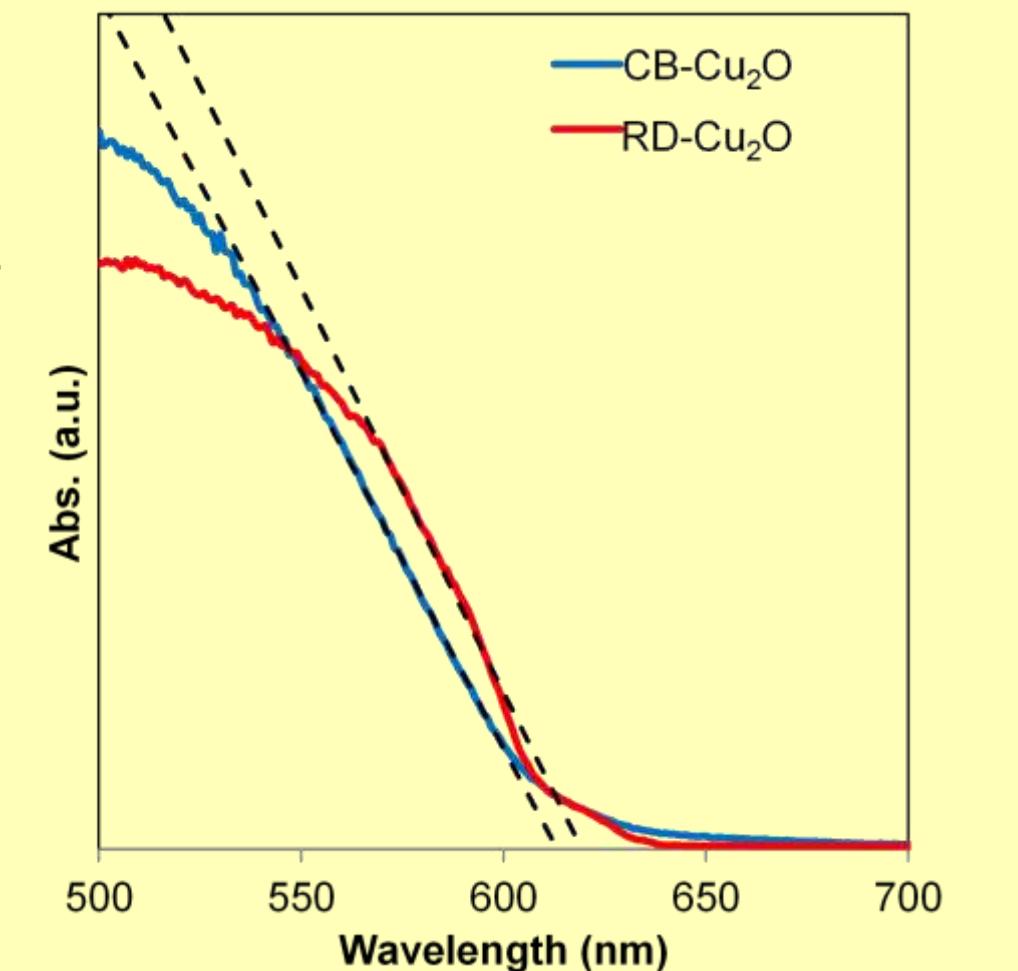
XRD

- ❖ Similar XRD patterns
- ❖ Cubic crystalline Cu₂O



UV-Vis

- ❖ Comparable absorption band edge
- ❖ Bandgap: ~2.0 eV

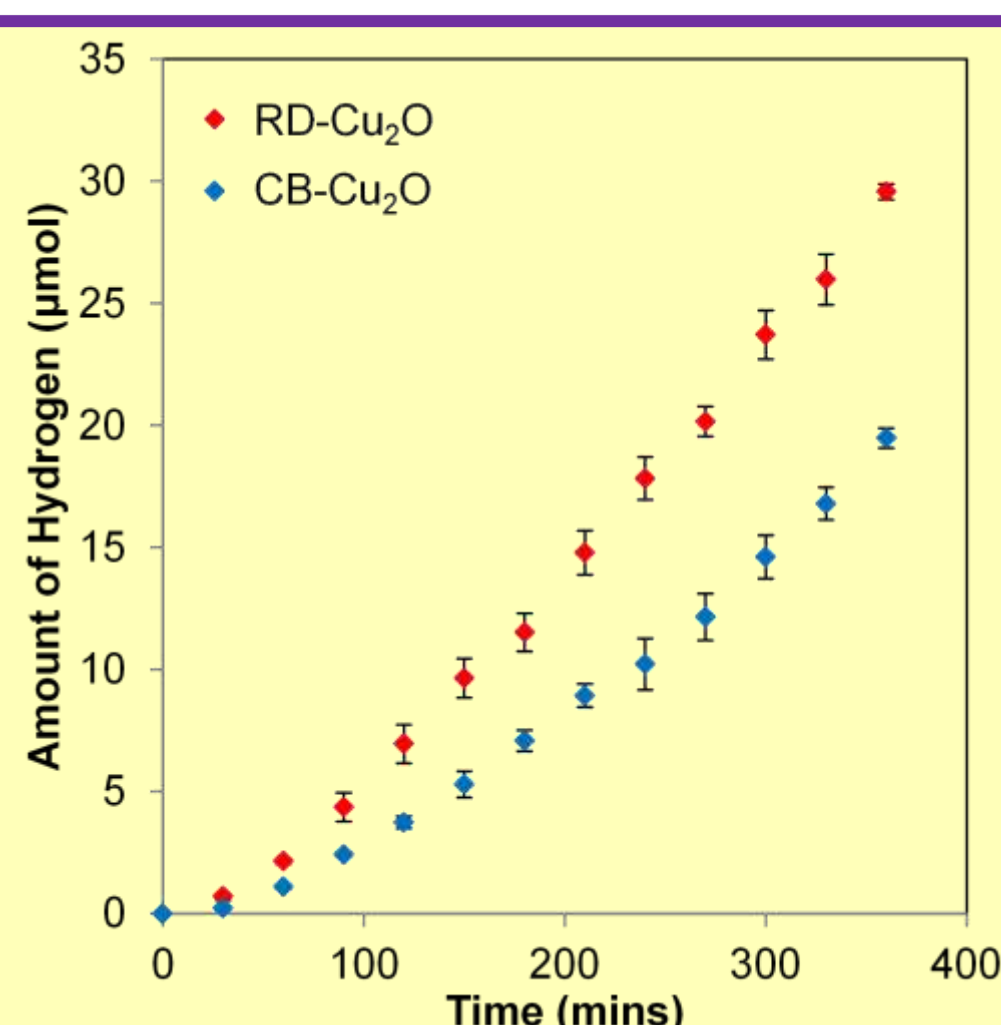


Photoactivity

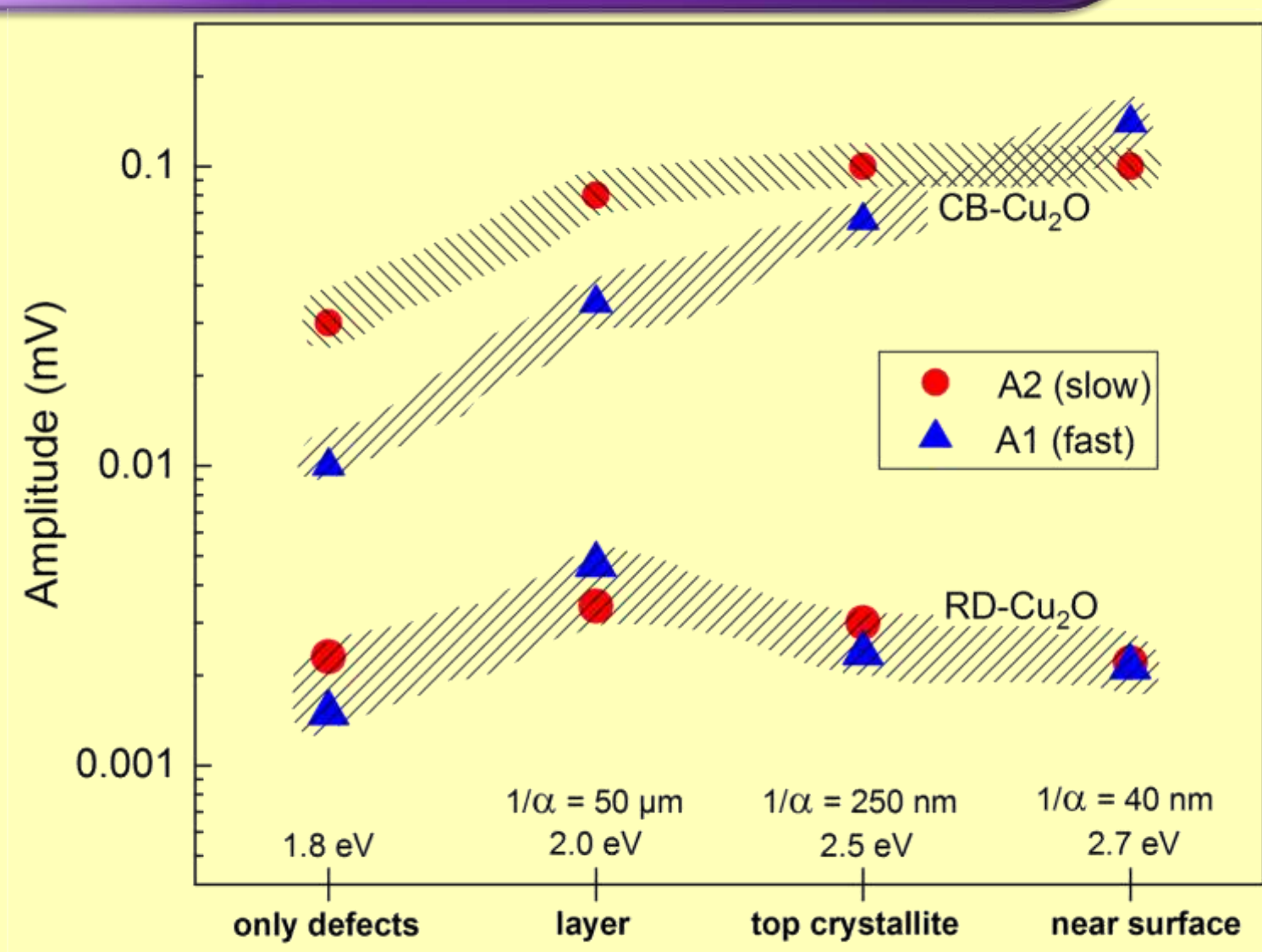
Photocatalytic H₂ Evolution

RD-Cu₂O: 29.6 μmol H₂
CB-Cu₂O: 19.5 μmol H₂

- ❖ RD-Cu₂O shows better performances.



Surface Photovoltage Measurement

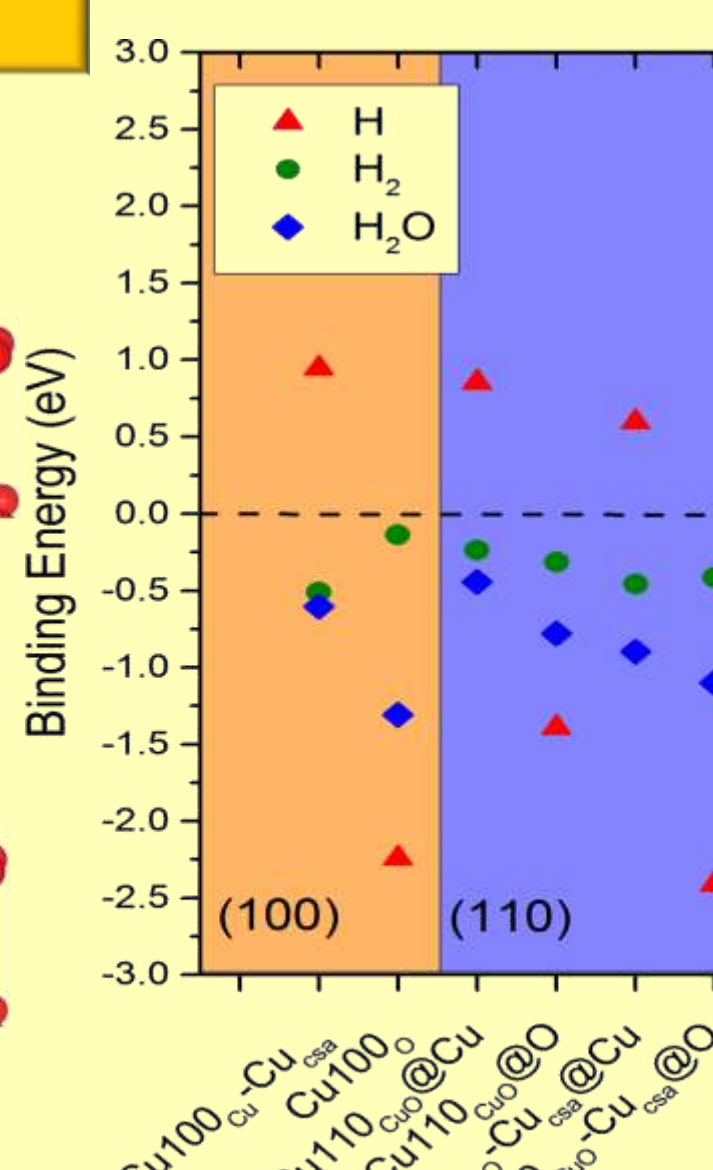
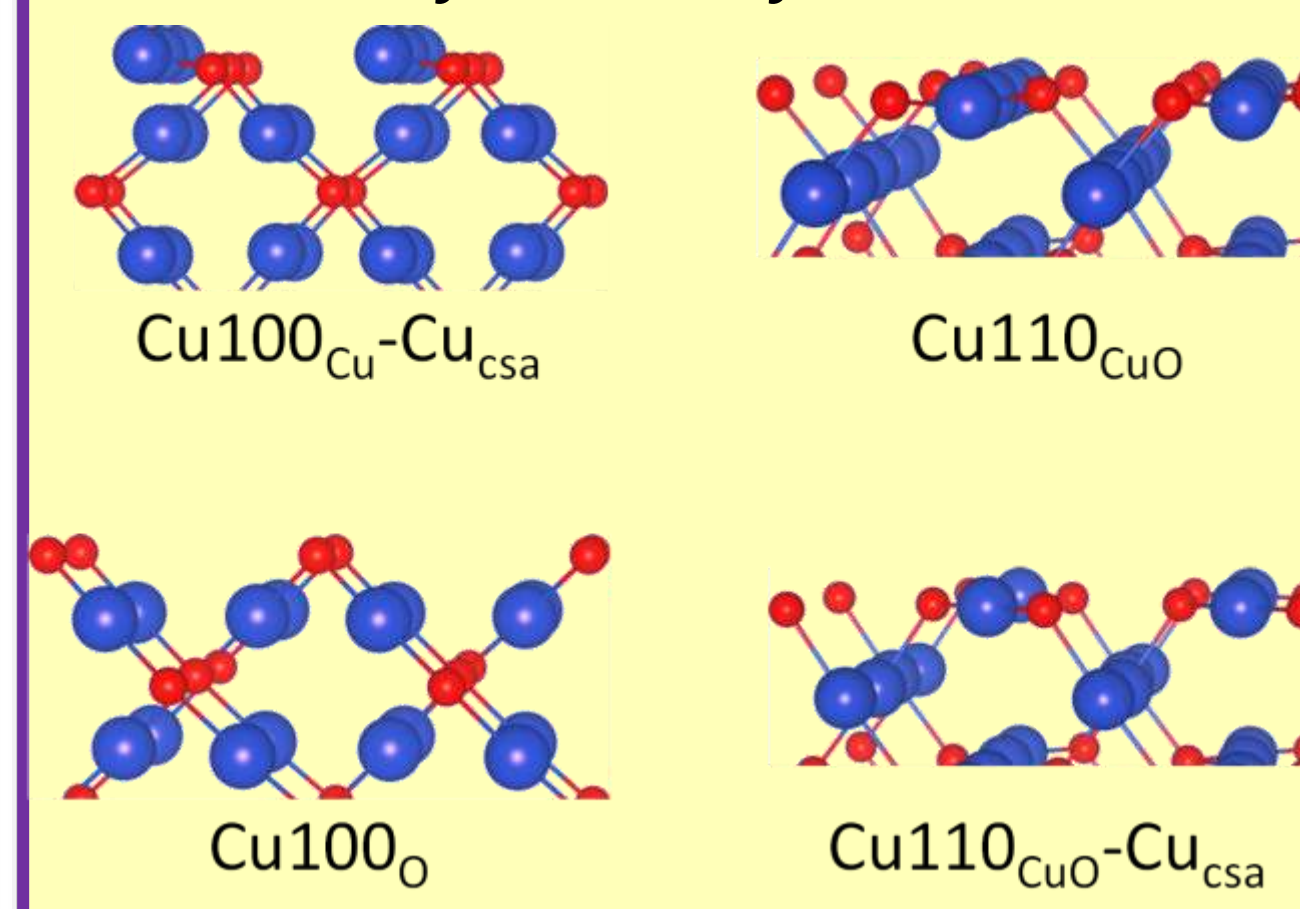


- ❖ RD-Cu₂O: **weak SPV** due to lower defect density.
- ❖ RD-Cu₂O: modulated charge distribution indicates **better charge transfer**.

Factors Influencing Photoactivity

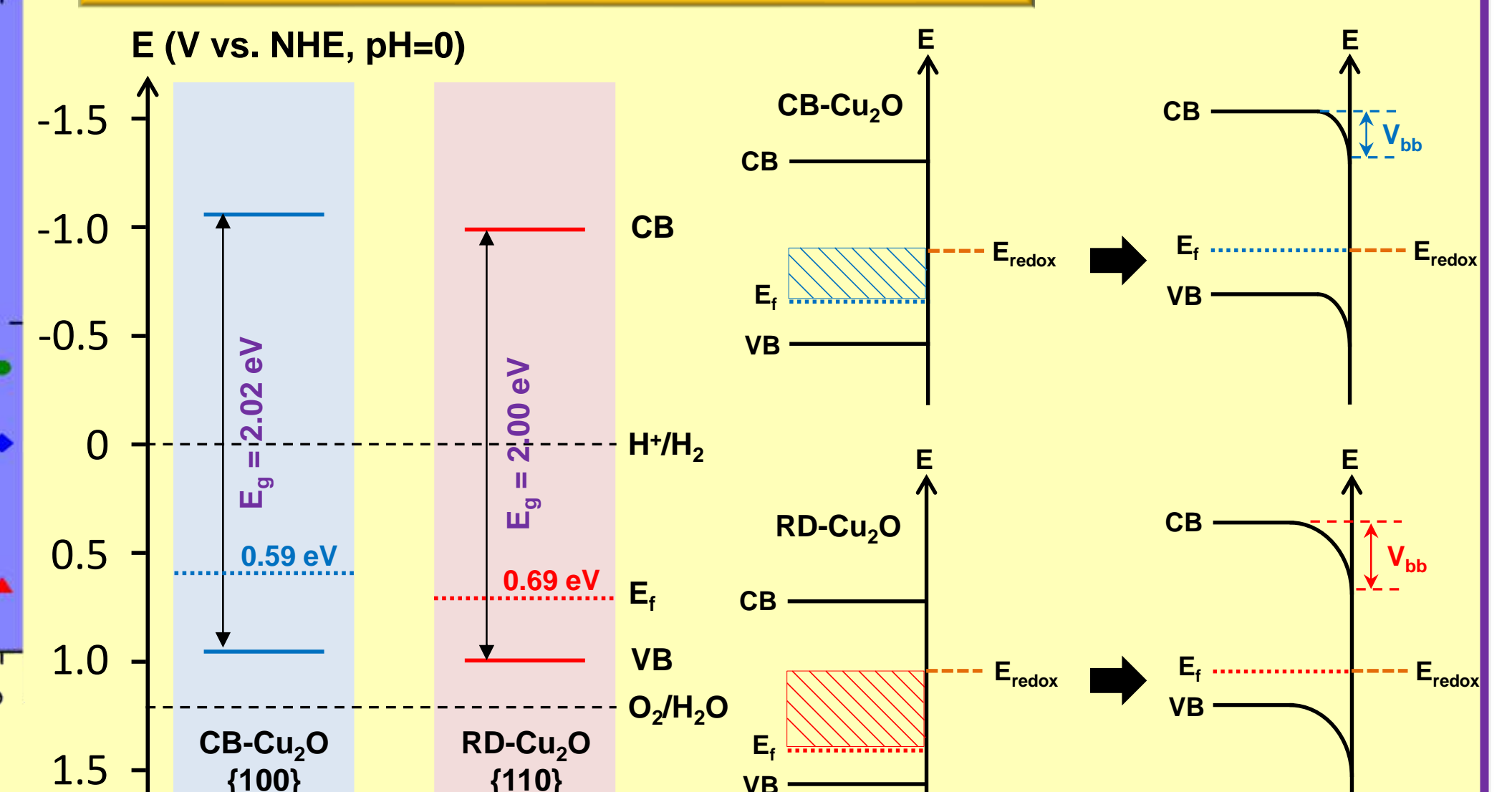
Surface Absorption Ability

Thermodynamically stable facets



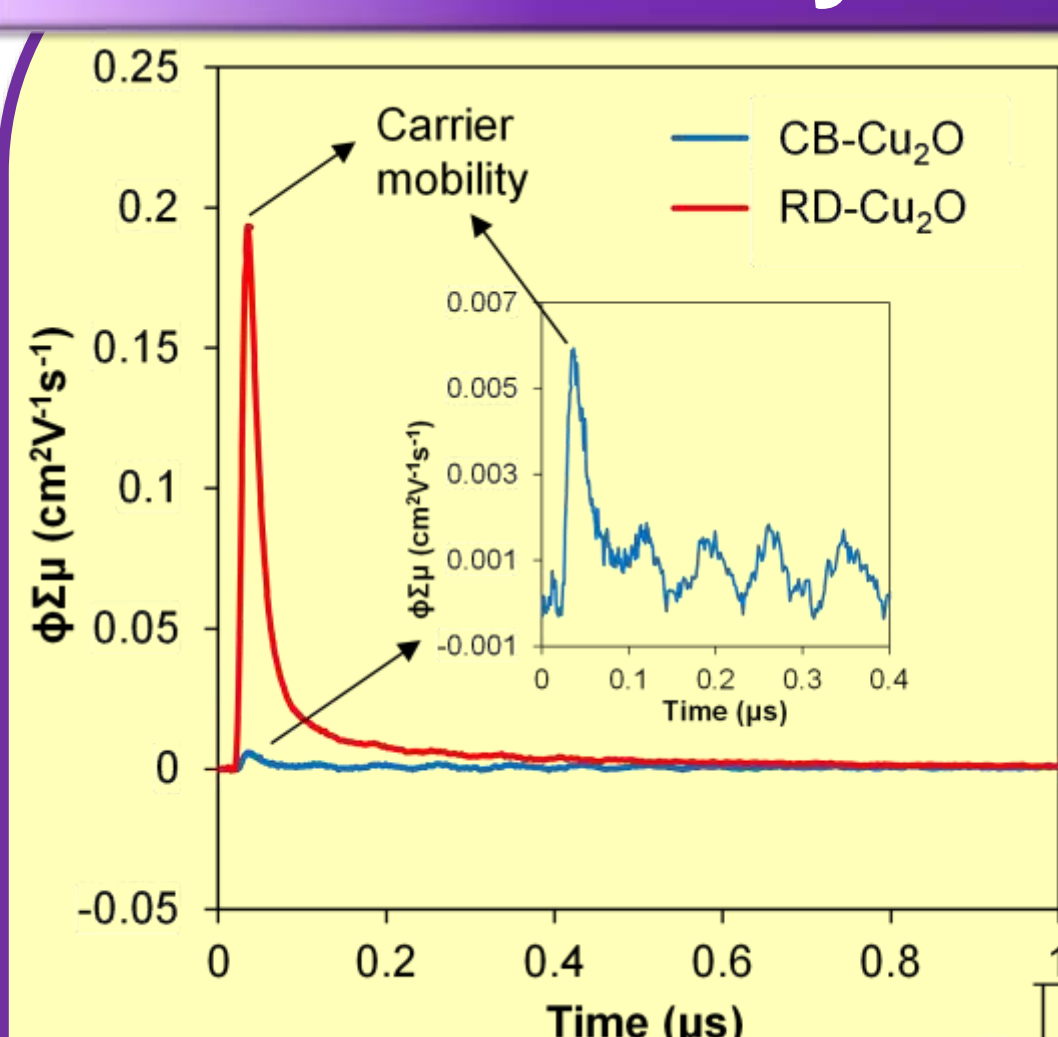
- ❖ Calculated using density of functional theory (DFT).
- ❖ By considering equal existence of these stable facets, surface adsorption ability of H, H₂ and H₂O **could not be greatly differentiated**.

Surface Electronic Structure



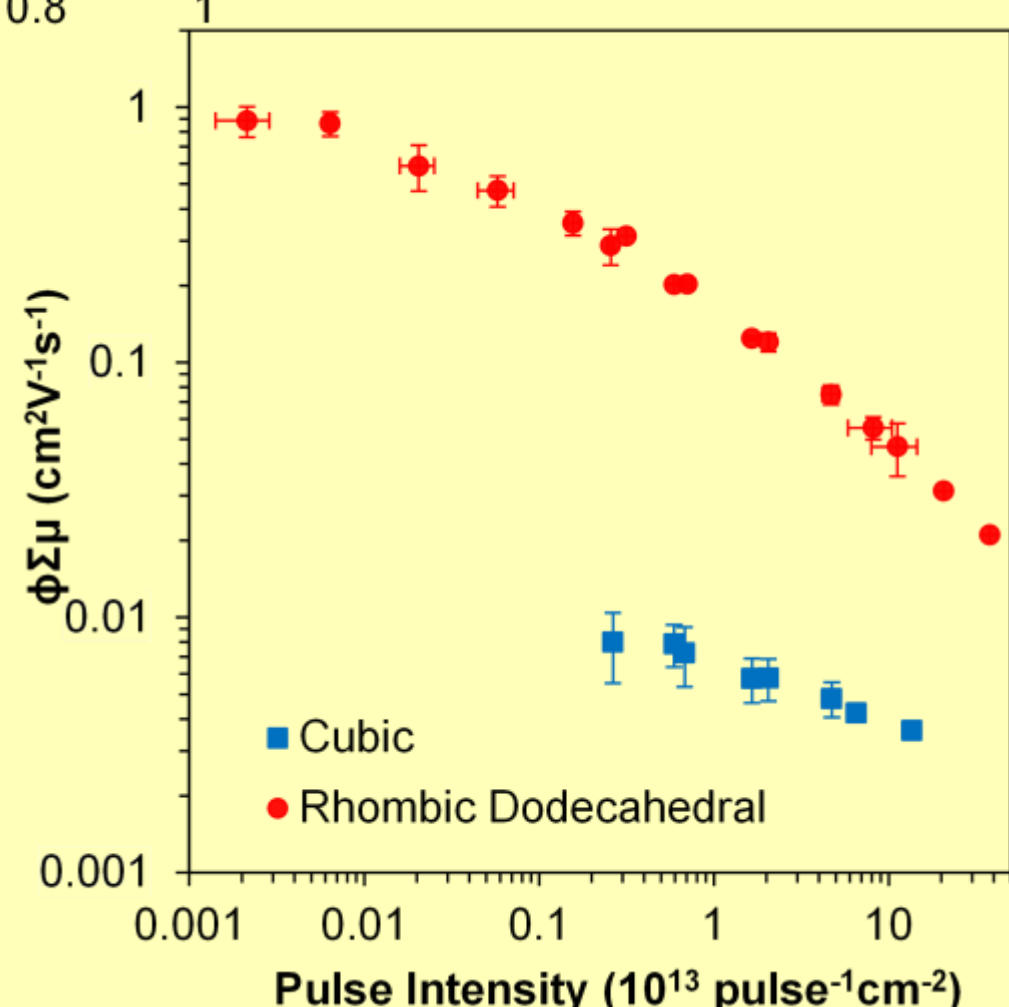
- ❖ Proposed band structures were identified by their bandgaps, valence bands computed from linear sweep voltammetry and valence XPS spectra.
- ❖ The larger band bending of RD-Cu₂O indicates its **better charge transfer** when compared to CB-Cu₂O.

Time-resolve Microwave Conductivity Measurement



- ❖ RD-Cu₂O show **higher carrier mobility**.
- ❖ Fitted carrier lifetime of RD-Cu₂O is **longer**.

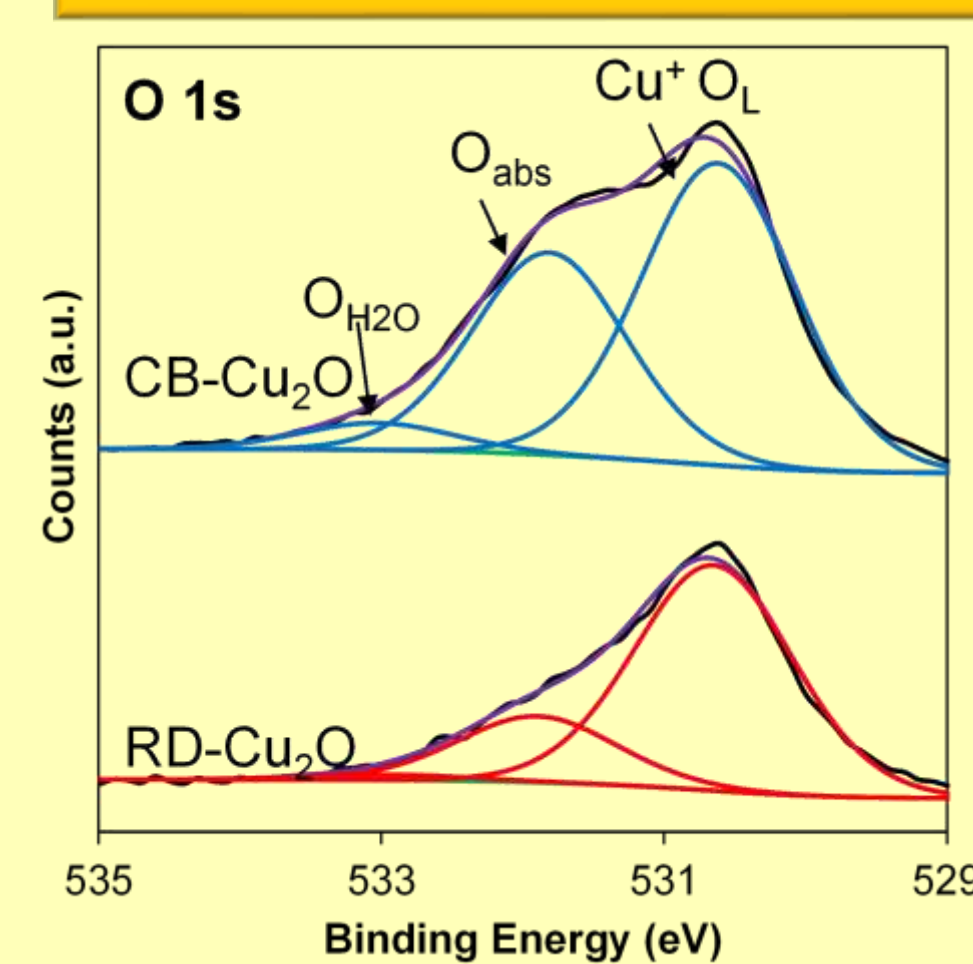
- ❖ RD-Cu₂O consistently show **2 orders of magnitude higher carrier mobility** throughout different laser pulse intensity.



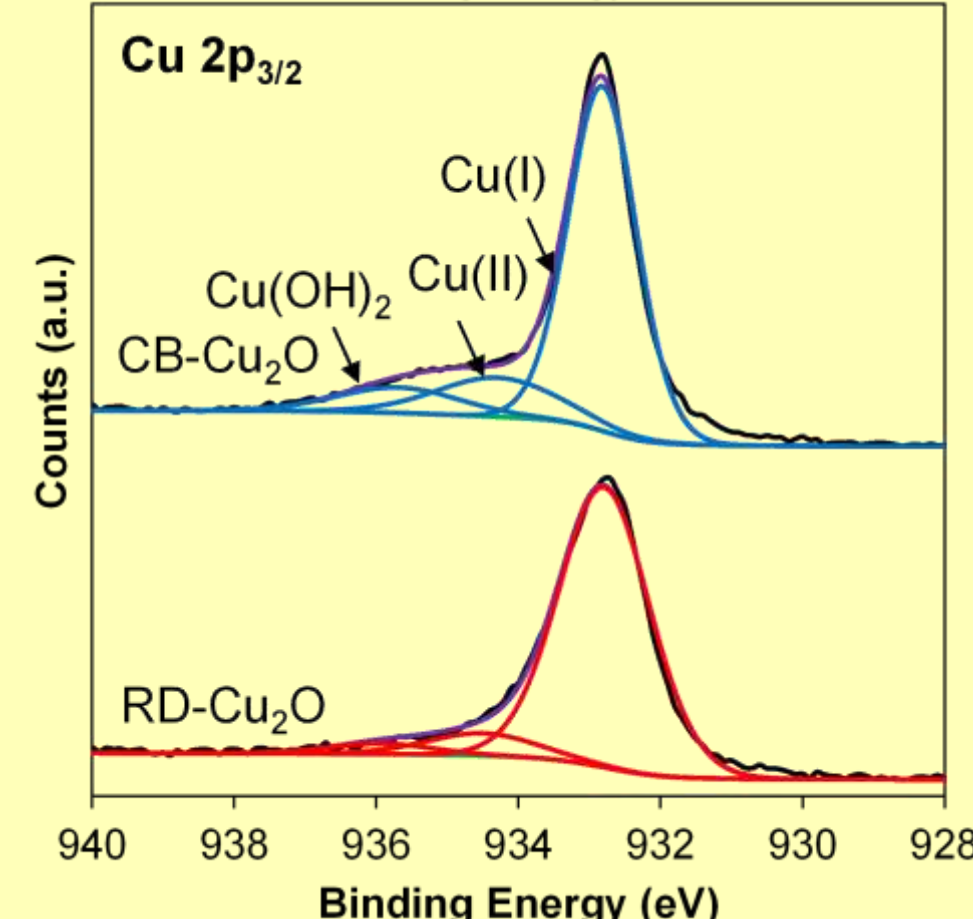
TRMC:

- Highly sensitive contactless approach that utilizes nanosecond pulsed laser to **determine the carrier mobility and lifetime** of a semiconductor.
- Measures the change in reflected microwave power which is expressed as product of internal quantum efficiency (ϕ) and the sum of carrier mobility ($\Sigma\mu$).

Surface Defect Density

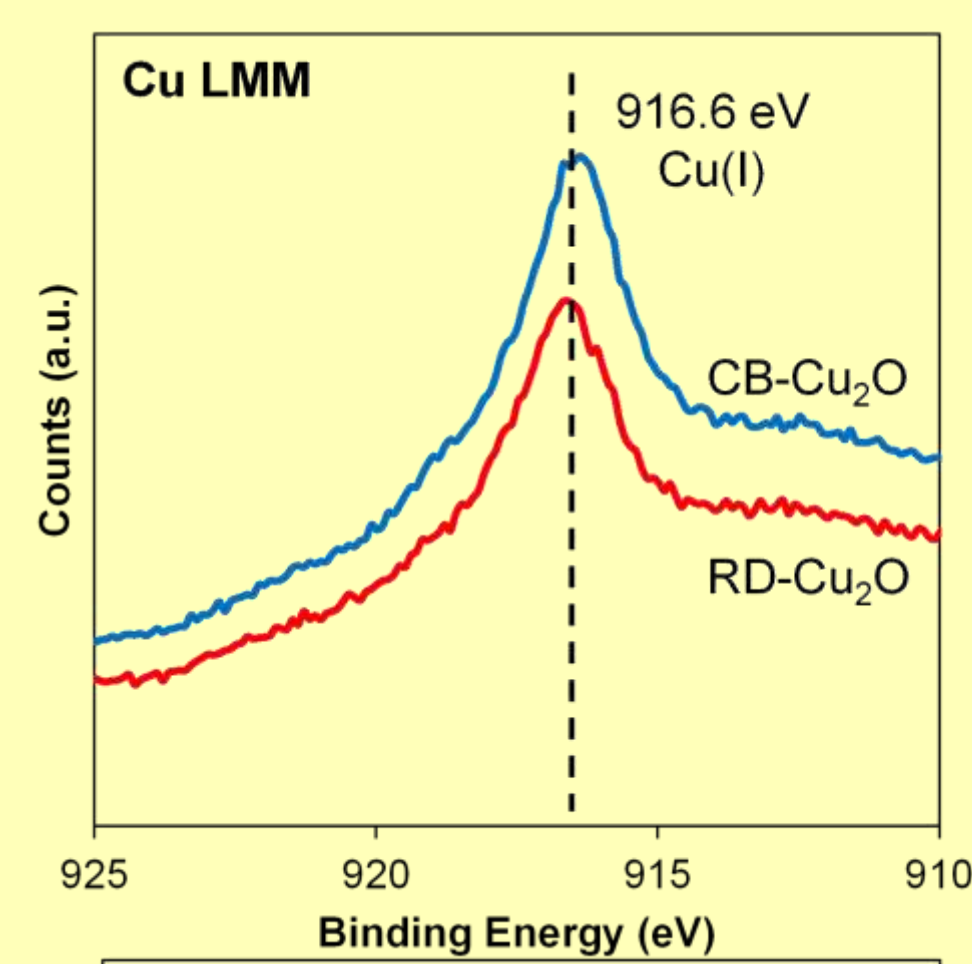


- ❖ O_{abs} is associated to the oxygen vacancies.
- ❖ O 1s spectra show **higher amount of oxygen vacancies** in CB-Cu₂O.

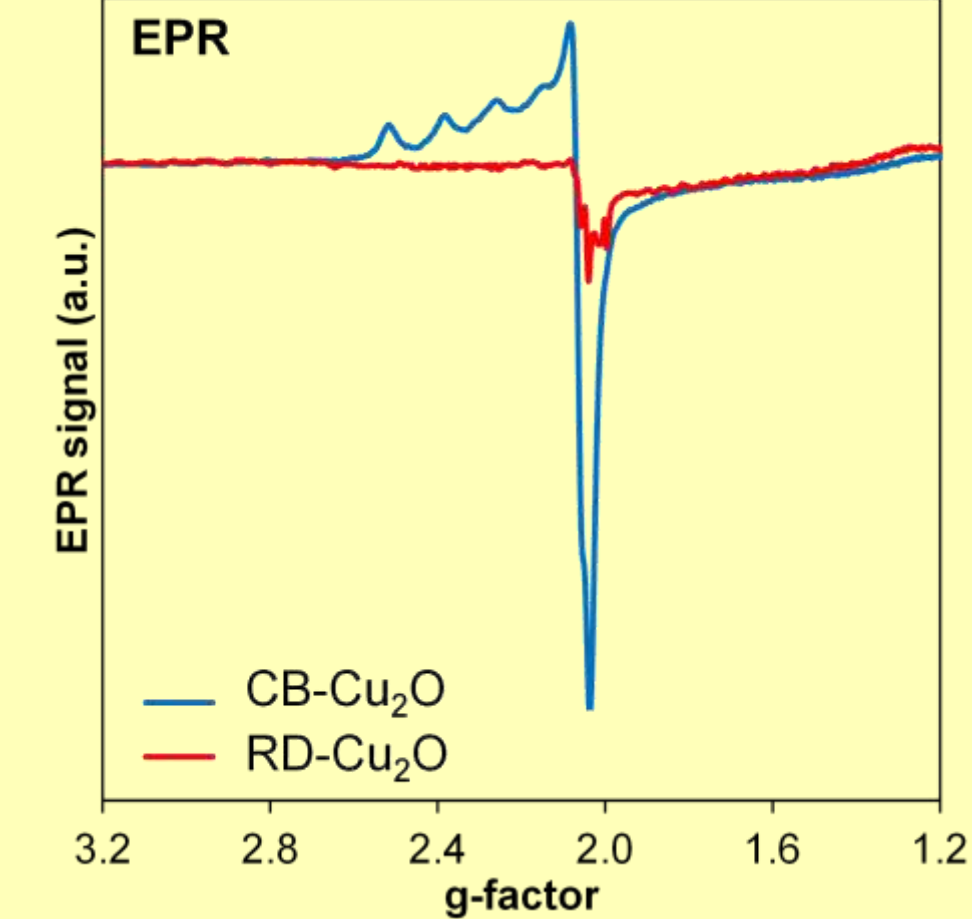


- ❖ Cu(II) indicates copper deficiency.
- ❖ Cu 2p spectra demonstrate **larger amount of copper defect (Cu²⁺)** in CB-Cu₂O.

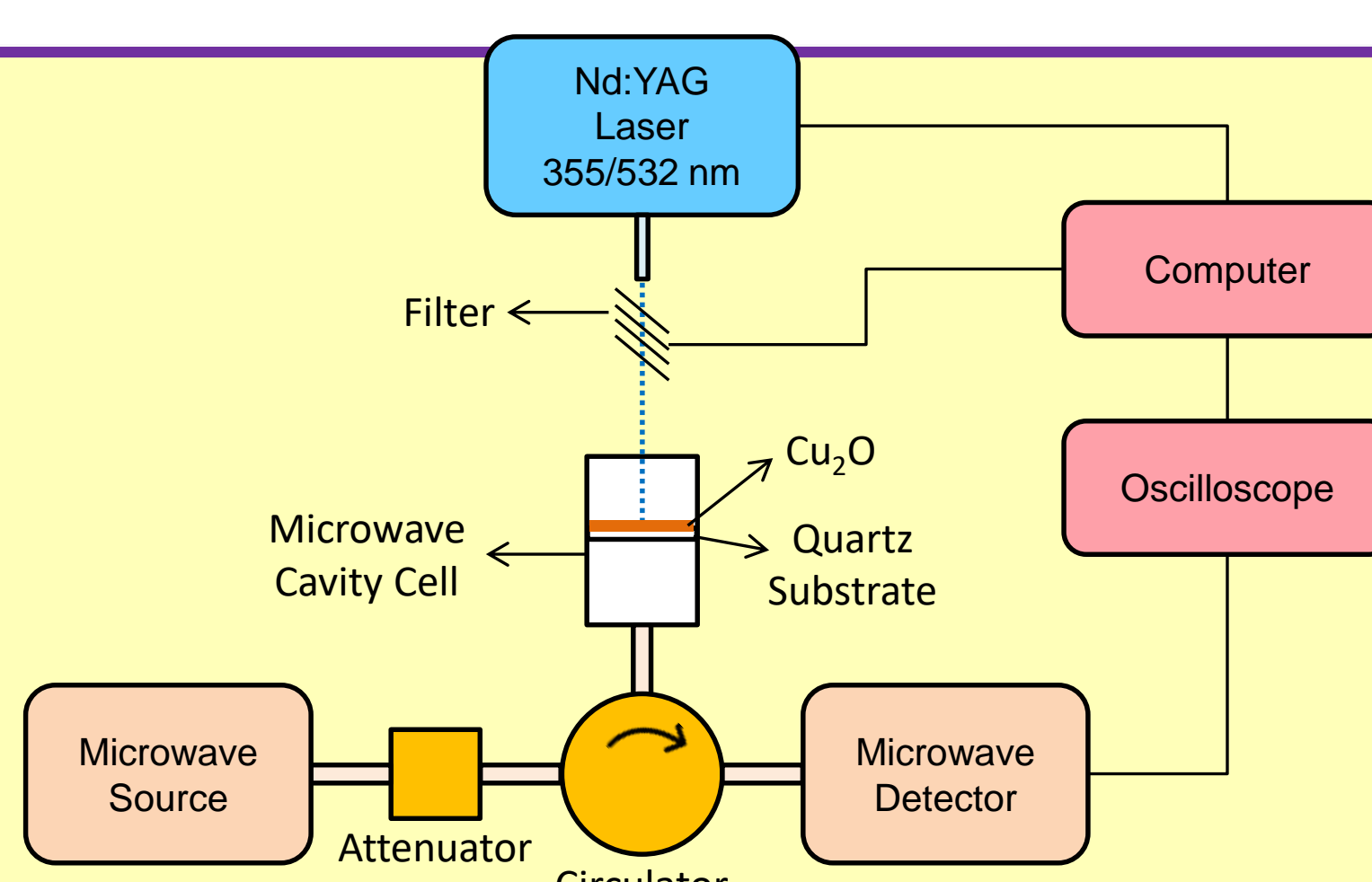
CB-Cu₂O has higher defect density than RD-Cu₂O.



- ❖ 916.6 eV corresponded to Cu₂O is the only peak observed in Cu LMM auger spectra.
- ❖ **No CuO species.**



- ❖ Cu²⁺ is paramagnetic species and can be detected by electron paramagnetic resonance (EPR) spectroscopy.
- ❖ **Intensified EPR signal** (g-value: 2.06) of CB-Cu₂O indicates its higher amount of copper defect.



Summary

- ❖ **RD-Cu₂O > CB-Cu₂O**
- ❖ Attributed to its **higher carrier mobility and better charge separation**, which is associated to its **lower surface defect density and different surface exposed facets**.
- ❖ This study shows that the **charge carrier dynamics** have deciding influence on photoactivity.